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PATTERN-BASED DEFECT DESCRIPTION METHOD

Abstract

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The present invention provides a method of describing defects that requires less memory space than conventional methods. Entries of a first defect table are sorted according to the type of track layout, or zones. They are then grouped into clusters. Each cluster is characterized by a set of new

15   parameters, including a starting sector, a scratch parameter, a span parameter, and an angle parameter. The new parameters are stored in a second table, replacing the corresponding entries in the first table. In this manner, a single entry in the second table replaces one or more entries in the first table with one entry in the first table.